

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination AMEMIYA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	Bertin, Eugene P. "Introduction to X-ray Spectrometric Analysis" Plenum Press, New York 1978, pp. 53,87,93-94.		
	V			
	W			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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